

Gaussian Processes

Seung-Hoon Na

Chonbuk National University

Gaussian Process Regression

- Predictions using noisy observations

$$\begin{pmatrix} y \\ \mathbf{f}_* \end{pmatrix} \sim \mathcal{N} \left(\mathbf{0}, \begin{pmatrix} \mathbf{K}_y & \mathbf{K}_* \\ \mathbf{K}_*^T & \mathbf{K}_{**} \end{pmatrix} \right)$$

$$p(\mathbf{f}_* | \mathbf{X}_*, \mathbf{X}, \mathbf{y}) = \mathcal{N}(\mathbf{f}_* | \boldsymbol{\mu}_*, \boldsymbol{\Sigma}_*)$$

$$\boldsymbol{\mu}_* = \mathbf{K}_*^T \mathbf{K}_y^{-1} \mathbf{y}$$

$$\boldsymbol{\Sigma}_* = \mathbf{K}_{**} - \mathbf{K}_*^T \mathbf{K}_y^{-1} \mathbf{K}_*$$

– The case of a single test input:

$$p(f_* | \mathbf{x}_*, \mathbf{X}, \mathbf{y}) = \mathcal{N}(f_* | \mathbf{k}_*^T \mathbf{K}_y^{-1} \mathbf{y}, k_{**} - \mathbf{k}_*^T \mathbf{K}_y^{-1} \mathbf{k}_*)$$

Gaussian Process Regression

- **Computational and numerical issues**
 - It is unwise to directly invert \mathbf{K}_y
 - Instead, we use a Cholesky decomposition $\mathbf{K}_y = \mathbf{L}\mathbf{L}^T$

Algorithm 15.1: GP regression

- 1 $\mathbf{L} = \text{cholesky}(\mathbf{K} + \sigma_y^2 \mathbf{I});$
 - 2 $\boldsymbol{\alpha} = \mathbf{L}^T \setminus (\mathbf{L} \setminus \mathbf{y});$
 - 3 $\mathbb{E}[f_*] = \mathbf{k}_*^T \boldsymbol{\alpha};$
 - 4 $\mathbf{v} = \mathbf{L} \setminus \mathbf{k}_*;$
 - 5 $\text{var}[f_*] = \kappa(\mathbf{x}_*, \mathbf{x}_*) - \mathbf{v}^T \mathbf{v};$
 - 6 $\log p(\mathbf{y}|\mathbf{X}) = -\frac{1}{2} \mathbf{y}^T \boldsymbol{\alpha} - \sum_i \log L_{ii} - \frac{N}{2} \log(2\pi)$
-

 Marginal probability

Gaussian Process Regression

- $f(x_*) = k_{**} - \mathbf{k}_*^T \mathbf{K}_y^{-1} \mathbf{k}_*$
- $\text{cholesky}(\mathbf{K}_y) = \mathbf{L}\mathbf{L}^T$
- $\mathbf{k}_*^T \mathbf{K}_y^{-1} \mathbf{k}_* = (\mathbf{L}^{-1} \mathbf{k}_*)^T (\mathbf{L}^{-1} \mathbf{k}_*)$
- $\mathbf{v} = \mathbf{L}^{-1} \mathbf{k}_* = \mathbf{L} \setminus \mathbf{k}_*$

Cholesky Decomposition


- The Cholesky decomposition(CD)
 - The CD of a symmetric, positive definite matrix A decomposes A into a product of a lower triangular matrix L and its transpose

$$LL^T = A$$

- Solving linear system using CD:

- To solve $A\mathbf{x} = \mathbf{b}$

- We have two steps: $L\mathbf{y} = \mathbf{b}$ $L^T\mathbf{x} = \mathbf{y}$


$$\mathbf{x} = L^T \setminus (L \setminus \mathbf{b})$$

- Computing the determinant of a matrix

$$|A| = \prod_{i=1}^n L_{ii}^2, \quad \text{or} \quad \log |A| = 2 \sum_{i=1}^n \log L_{ii}$$

Gaussian Process Classification

- The main difficulty is that the Gaussian prior is not conjugate to the bernoulli/ multinoulli likelihood → several approximations are available
 - **Gaussian approximation**
 - Expectation propagation (Kuss and Rasmussen 2005; Nickisch and Rasmussen 2008)
 - Variational inference (Girolami and Rogers 2006; Opper and Archambeau 2009)
 - MCMC (Neal 1997; Christensen et al. 2006)

Gaussian Process Classification

binary classification

$$p(y_i|\mathbf{x}_i) = \sigma(y_i f(\mathbf{x}_i))$$

- Logistic regression: $\sigma(z) = \text{sigm}(z)$
- Probit regression: $\sigma(z) = \Phi(z)$
- f : GP regression $f \sim \text{GP}(0, \kappa)$

Gaussian Process Classification

- Define the log of the unnormalized posterior

$$\ell(\mathbf{f}) = \log p(\mathbf{y}|\mathbf{f}) + \log p(\mathbf{f}|\mathbf{X})$$

$$= \log p(\mathbf{y}|\mathbf{f}) - \frac{1}{2}\mathbf{f}^T \mathbf{K}^{-1} \mathbf{f} - \frac{1}{2} \log |\mathbf{K}| - \frac{N}{2} \log 2\pi$$

$$J(f) \triangleq -\ell(f)$$

$$\mathbf{g} = -\nabla \log p(\mathbf{y}|\mathbf{f}) + \mathbf{K}^{-1} \mathbf{f}$$

$$\mathbf{H} = -\nabla \nabla \log p(\mathbf{y}|\mathbf{f}) + \mathbf{K}^{-1} = \mathbf{W} + \mathbf{K}^{-1}$$

$$\mathbf{W} \triangleq -\nabla \nabla \log p(\mathbf{y}|\mathbf{f})$$

Gaussian Process Classification

- Formula for $\nabla \log p(\mathbf{y}|\mathbf{f})$ $\nabla \nabla \log p(\mathbf{y}|\mathbf{f})$

| $\log p(y_i f_i)$ | $\frac{\partial}{\partial f_i} \log p(y_i f_i)$ | $\frac{\partial^2}{\partial f_i^2} \log p(y_i f_i)$ |
|-----------------------------|---|---|
| $\log \text{sigm}(y_i f_i)$ | $t_i - \pi_i$ | $-\pi_i(1 - \pi_i)$ |
| $\log \Phi(y_i f_i)$ | $\frac{y_i \phi(f_i)}{\Phi(y_i f_i)}$ | $-\frac{\phi_i^2}{\Phi(y_i f_i)^2} - \frac{y_i f_i \phi(f_i)}{\Phi(y_i f_i)}$ |

Gaussian Process Classification

- Use IRLS to find the MAP estimate

$$\begin{aligned}\mathbf{f}^{new} &= \mathbf{f} - \mathbf{H}^{-1}\mathbf{g} \\ &= \mathbf{f} + (\mathbf{K}^{-1} + \mathbf{W})^{-1}(\nabla \log p(\mathbf{y}|\mathbf{f}) - \mathbf{K}^{-1}\mathbf{f}) \\ &= (\mathbf{K}^{-1} + \mathbf{W})^{-1}(\mathbf{W}\mathbf{f} + \nabla \log p(\mathbf{y}|\mathbf{f}))\end{aligned}$$

- At convergence, the Gaussian approximation of the posterior:

$$p(\mathbf{f}|\mathbf{X}, \mathbf{y}) \approx \mathcal{N}(\hat{\mathbf{f}}, (\mathbf{K}^{-1} + \mathbf{W})^{-1})$$

Gaussian Process Classification

- **Computing the posterior predictive**
- The predictive mean:

$$\begin{aligned}\mathbb{E} [f_* | \mathbf{x}_*, \mathbf{X}, \mathbf{y}] &= \int \mathbb{E} [f_* | \mathbf{f}, \mathbf{x}_*, \mathbf{X}, \mathbf{y}] p(\mathbf{f} | \mathbf{X}, \mathbf{y}) d\mathbf{f} \\ &= \int \mathbf{k}_*^T \mathbf{K}^{-1} \mathbf{f} p(\mathbf{f} | \mathbf{X}, \mathbf{y}) d\mathbf{f} \\ &= \mathbf{k}_*^T \mathbf{K}^{-1} \mathbb{E} [\mathbf{f} | \mathbf{X}, \mathbf{y}] \approx \mathbf{k}_*^T \mathbf{K}^{-1} \hat{\mathbf{f}}\end{aligned}$$

Gaussian Process Classification

- The predictive variance:
 - Use the law of total variance

$$\text{var} [f_*] = \mathbb{E} [\text{var} [f_* | \mathbf{f}]] + \text{var} [\mathbb{E} [f_* | \mathbf{f}]]$$

$$\begin{aligned} \mathbb{E} [\text{var} [f_* | \mathbf{f}]] &= \mathbb{E} [k_{**} - \mathbf{k}_*^T \mathbf{K}^{-1} \mathbf{k}_*] \\ &= k_{**} - \mathbf{k}_*^T \mathbf{K}^{-1} \mathbf{k}_* \end{aligned}$$

$$\begin{aligned} \text{var} [\mathbb{E} [f_* | \mathbf{f}]] &= \text{var} [\mathbf{k}_* \mathbf{K}^{-1} \mathbf{f}] \\ &= \mathbf{k}_*^T \mathbf{K}^{-1} \text{cov} [\mathbf{f}] \mathbf{K}^{-1} \mathbf{k}_* \end{aligned}$$

Gaussian Process Classification

- The predictive variance:

$$\text{var} [f_*] = k_{**} - \mathbf{k}_*^T (\mathbf{K}^{-1} - \mathbf{K}^{-1} \text{cov} [\mathbf{f}] \mathbf{K}^{-1}) \mathbf{k}_*$$

$$\text{cov} [f] \approx (\mathbf{K}^{-1} + \mathbf{W})^{-1}$$

$$\text{var} [f_*]$$

$$\approx k_{**} - \mathbf{k}_*^T \mathbf{K}^{-1} \mathbf{k}_* + \mathbf{k}_*^T \mathbf{K}^{-1} (\mathbf{K}^{-1} + \mathbf{W})^{-1} \mathbf{K}^{-1} \mathbf{k}_*$$

$$= k_{**} - \mathbf{k}_*^T (\mathbf{K} + \mathbf{W}^{-1})^{-1} \mathbf{k}_* \quad \leftarrow \text{Matrix inversion lemma}$$

Matrix inversion lemma

- Consider a general partitioned matrix $\mathbf{M} = \begin{pmatrix} \mathbf{E} & \mathbf{F} \\ \mathbf{G} & \mathbf{H} \end{pmatrix}$

where we assume \mathbf{E} and \mathbf{H} are invertible

$$(\mathbf{E} - \mathbf{F}\mathbf{H}^{-1}\mathbf{G})^{-1} = \mathbf{E}^{-1} + \mathbf{E}^{-1}\mathbf{F}(\mathbf{H} - \mathbf{G}\mathbf{E}^{-1}\mathbf{F})^{-1}\mathbf{G}\mathbf{E}^{-1}$$

$$(\mathbf{E} - \mathbf{F}\mathbf{H}^{-1}\mathbf{G})^{-1}\mathbf{F}\mathbf{H}^{-1} = \mathbf{E}^{-1}\mathbf{F}(\mathbf{H} - \mathbf{G}\mathbf{E}^{-1}\mathbf{F})^{-1}$$

$$|\mathbf{E} - \mathbf{F}\mathbf{H}^{-1}\mathbf{G}| = |\mathbf{H} - \mathbf{G}\mathbf{E}^{-1}\mathbf{F}||\mathbf{H}^{-1}||\mathbf{E}|$$

Gaussian Process Classification

$$p(f_* | \mathbf{x}_*, \mathbf{X}, \mathbf{y}) = \mathcal{N}(\mathbb{E}[f_*], \text{var}[f_*])$$

- Convert to a predictive distribution for binary responses

$$\begin{aligned}\pi_* &= p(y_* = 1 | \mathbf{x}_*, \mathbf{X}, \mathbf{y}) \\ &\approx \int \sigma(f_*) p(f_* | \mathbf{x}_*, \mathbf{X}, \mathbf{y}) df_*\end{aligned}$$

- This can be approximated using
 - Monte Carlo approximation
 - Probit approximation
 - ...

Gaussian Process Classification

- Marginal likelihood
 - Used to optimize the kernel parameters
 - Applying the Laplace approximation, we have:

$$\log p(\mathbf{y}|\mathbf{X}) \approx \ell(\hat{\mathbf{f}}) - \frac{1}{2} \log |\mathbf{H}| + \text{const}$$

$$\log p(\mathbf{y}|\mathbf{X}) \approx \log p(\mathbf{y}|\hat{\mathbf{f}}) - \frac{1}{2} \hat{\mathbf{f}}^T \mathbf{K}^{-1} \hat{\mathbf{f}} - \frac{1}{2} \log |\mathbf{K}| - \frac{1}{2} \log |\mathbf{K}^{-1} + \mathbf{W}|$$

- Computing the derivatives $\frac{\partial \log p(\mathbf{y}|\mathbf{X}, \boldsymbol{\theta})}{\partial \theta_j}$
 - Now, since $\hat{\mathbf{f}}$, \mathbf{W} , as well as \mathbf{K} , depend on $\boldsymbol{\theta}$
 - More complex than in the regression case

Gaussian Process Classification

- **Laplace approximation** to the marginal likelihood.

$$\begin{aligned}\hat{p}(\boldsymbol{\theta}|\mathcal{D}) &\approx \frac{1}{Z} e^{-E(\boldsymbol{\theta}^*)} \exp \left[-\frac{1}{2} (\boldsymbol{\theta} - \boldsymbol{\theta}^*)^T \mathbf{H} (\boldsymbol{\theta} - \boldsymbol{\theta}^*) \right] \\ &= \mathcal{N}(\boldsymbol{\theta}|\boldsymbol{\theta}^*, \mathbf{H}^{-1}) \\ Z = p(\mathcal{D}) &\approx \int \hat{p}(\boldsymbol{\theta}|\mathcal{D}) d\boldsymbol{\theta} = e^{-E(\boldsymbol{\theta}^*)} (2\pi)^{D/2} |\mathbf{H}|^{-\frac{1}{2}}\end{aligned}$$

Gaussian Process Classification

- Numerically stable computation

- To avoid inverting \mathbf{K} or \mathbf{W} , introduce using \mathbf{B} :

$$\mathbf{B} = \mathbf{I}_N + \mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{W}^{\frac{1}{2}}$$

- \mathbf{B} : has eigenvalues bounded below by 1 and can be safely inverted

- Applying the matrix inversion lemma, we have:

$$(\mathbf{K}^{-1} + \mathbf{W})^{-1} = \mathbf{K} - \mathbf{K} \mathbf{W}^{\frac{1}{2}} \mathbf{B}^{-1} \mathbf{W}^{\frac{1}{2}} \mathbf{K}$$

- The IRLS update, now:

$$\mathbf{f}^{new} = (\mathbf{K}^{-1} + \mathbf{W})^{-1} \underbrace{(\mathbf{W} \mathbf{f} + \nabla \log p(\mathbf{y} | \mathbf{f}))}_{\mathbf{b}}$$

$$\begin{aligned} \mathbf{B} = \mathbf{L} \mathbf{L}^T & \rightarrow = \mathbf{K} (\mathbf{I} - \mathbf{W}^{\frac{1}{2}} \mathbf{B}^{-1} \mathbf{W}^{\frac{1}{2}} \mathbf{K}) \mathbf{b} \\ & = \mathbf{K} \underbrace{(\mathbf{b} - \mathbf{W}^{\frac{1}{2}} \mathbf{L}^T \setminus (\mathbf{L} \setminus (\mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{b})))}_{\mathbf{a}} \end{aligned}$$

Gaussian Process Classification

- Numerically stable computation


- At convergence, we have:

$$\mathbf{a} = \mathbf{K}^{-1} \hat{\mathbf{f}}$$

- The log-marginal likelihood is:

$$\log p(\mathbf{y}|\mathbf{X}) = \log p(\mathbf{y}|\hat{\mathbf{f}}) - \frac{1}{2} \mathbf{a}^T \hat{\mathbf{f}} - \sum_i \log L_{ii}$$

where we exploited:

$$|\mathbf{B}| = |\mathbf{K}| |\mathbf{K}^{-1} + \mathbf{W}| = |\mathbf{I}_N + \mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{W}^{\frac{1}{2}}|$$


Gaussian Process Classification

- Numerically stable computation

- Compute the predictive distr. $\mathbb{E}[f_*] = \mathbf{k}_*^T \mathbf{K}^{-1} \hat{\mathbf{f}}$

- Here, at the mode, $\nabla \ell = 0$, so $\hat{\mathbf{f}} = \mathbf{K}(\nabla \log p(\mathbf{y}|\hat{\mathbf{f}}))$

- Thus, the predictive mean:


$$\mathbb{E}[f_*] = \mathbf{k}_*^T \nabla \log p(\mathbf{y}|\hat{\mathbf{f}})$$

- Also, we use:

$$\begin{aligned} (\mathbf{K} + \mathbf{W}^{-1})^{-1} &= \mathbf{W}^{\frac{1}{2}} \mathbf{W}^{-\frac{1}{2}} (\mathbf{K} + \mathbf{W}^{-1})^{-1} \mathbf{W}^{-\frac{1}{2}} \mathbf{W}^{\frac{1}{2}} \\ &= \mathbf{W}^{\frac{1}{2}} \mathbf{B}^{-1} \mathbf{W}^{\frac{1}{2}} \end{aligned}$$

- Thus, the predictive variance:

$$\text{var}[f_*] = k_{**} - \mathbf{k}_*^T \mathbf{W}^{\frac{1}{2}} (\mathbf{L}\mathbf{L}^T)^{-1} \mathbf{W}^{\frac{1}{2}} \mathbf{k}_* = k_{**} - \mathbf{v}^T \mathbf{v}$$

$\mathbf{v} = \mathbf{L} \setminus (\mathbf{W}^{\frac{1}{2}} \mathbf{k}_*)$ 

Gaussian Process Classification

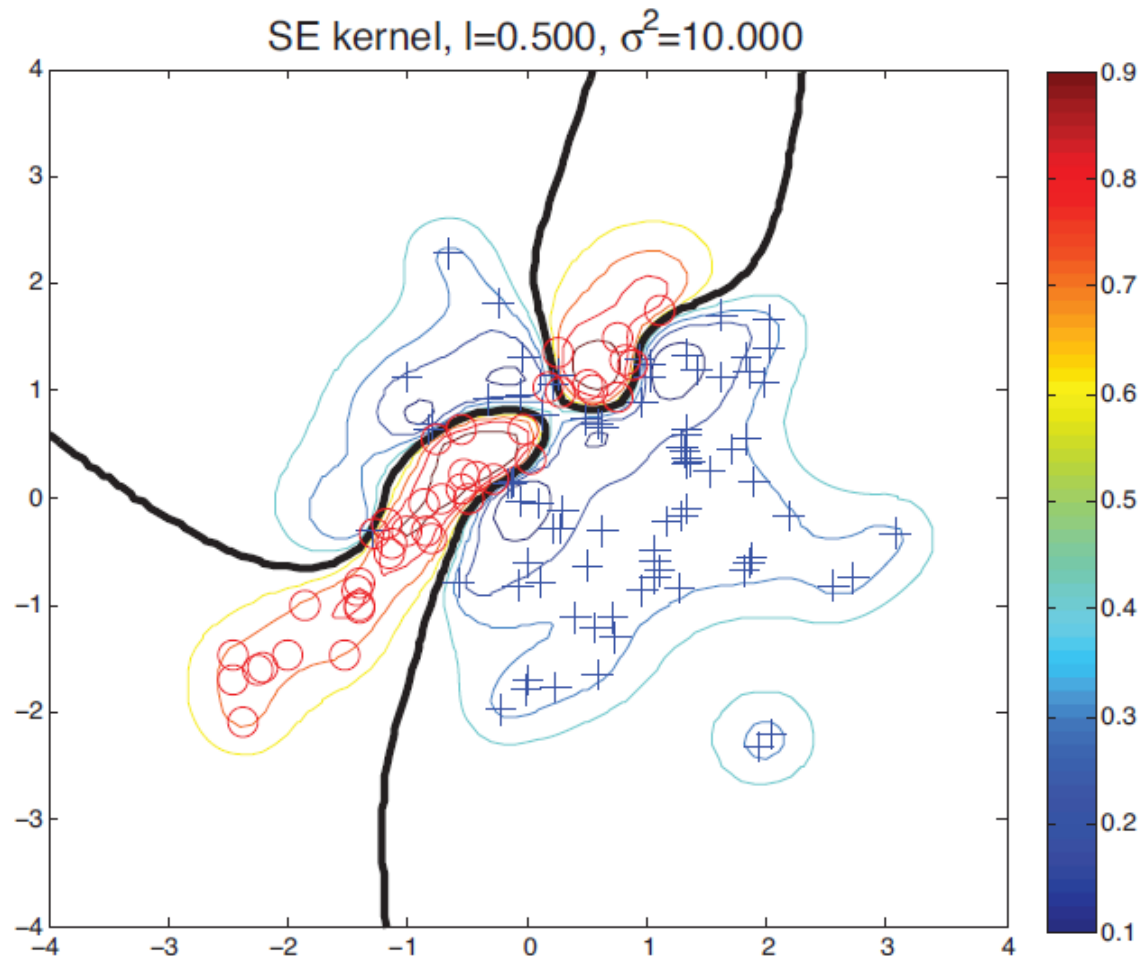
Algorithm 15.2: GP binary classification using Gaussian approximation

```
1 // First compute MAP estimate using IRLS;
2  $\mathbf{f} = \mathbf{0}$ ;
3 repeat
4    $\mathbf{W} = -\nabla\nabla \log p(\mathbf{y}|\mathbf{f})$  ;
5    $\mathbf{B} = \mathbf{I}_N + \mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{W}^{\frac{1}{2}}$  ;
6    $\mathbf{L} = \text{cholesky}(\mathbf{B})$  ;
7    $\mathbf{b} = \mathbf{W}\mathbf{f} + \nabla \log p(\mathbf{y}|\mathbf{f})$  ;
8    $\mathbf{a} = \mathbf{b} - \mathbf{W}^{\frac{1}{2}} \mathbf{L}^T \setminus (\mathbf{L} \setminus (\mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{b}))$ ;
9    $\mathbf{f} = \mathbf{K} \mathbf{a}$ ;
10 until converged;
11  $\log p(\mathbf{y}|\mathbf{X}) = \log p(\mathbf{y}|\mathbf{f}) - \frac{1}{2} \mathbf{a}^T \mathbf{f} - \sum_i \log L_{ii}$ ;
12 // Now perform prediction ;
13  $\mathbb{E}[f_*] = \mathbf{k}_*^T \nabla \log p(\mathbf{y}|\mathbf{f})$ ;
14  $\mathbf{v} = \mathbf{L} \setminus (\mathbf{W}^{\frac{1}{2}} \mathbf{k}_*)$ ;
15  $\text{var}[f_*] = k_{**} - \mathbf{v}^T \mathbf{v}$  ;
16  $p(y_* = 1) = \int \text{sigm}(z) \mathcal{N}(z | \mathbb{E}[f_*], \text{var}[f_*]) dz$ ;
```

Gaussian Process Classification

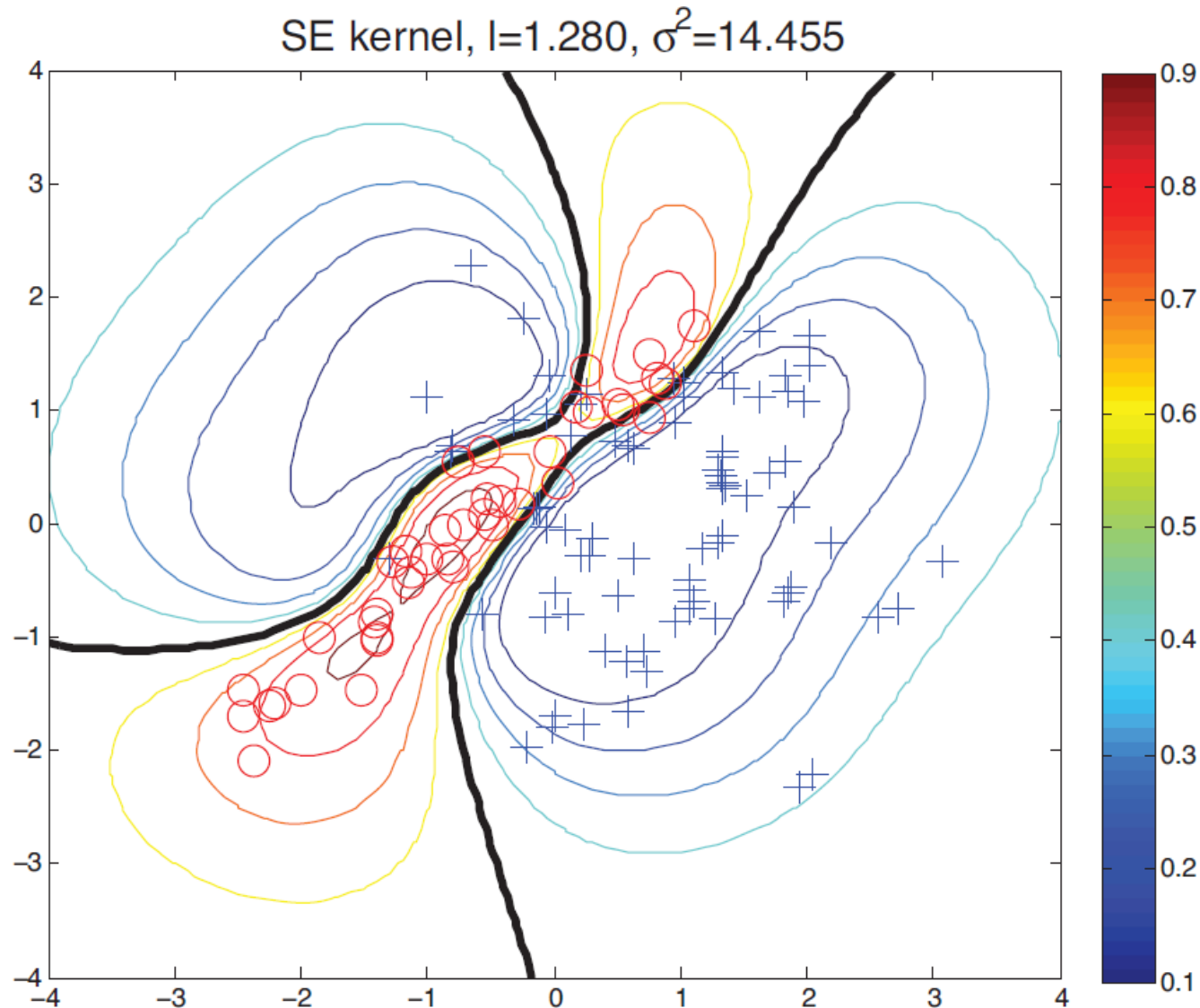
The posterior predictive probability for the red circle class generated by a GP with an SE kernel. Thick black line is the decision boundary if we threshold at a probability of 0.5.

- Manual parameters, short length scale.



Gaussian Process Classification

- Learned parameters, long length scale



Gaussian Process Classification:

Multi-class classification

$$p(y_i | \mathbf{x}_i) = \text{Cat}(y_i | \mathcal{S}(\mathbf{f}_i))$$

$$\mathbf{f}_i = (f_{i1}, \dots, f_{iC})$$

$$f_{.c} \sim \text{GP}(0, \kappa_c)$$

- Again, we will use a Gaussian approximation to the posterior
 - 1) Use IRLS to compute the mode
 - 2) Apply the Gaussian approximation at the mode

Gaussian Process Classification:

Multi-class classification

- The unnormalized log posterior:

$$\ell(\mathbf{f}) = -\frac{1}{2}\mathbf{f}^T \mathbf{K}^{-1} \mathbf{f} + \mathbf{y}^T \mathbf{f} - \sum_{i=1}^N \log \left(\sum_{c=1}^C \exp f_{ic} \right) - \frac{1}{2} \log |\mathbf{K}| - \frac{CN}{2} \log 2\pi$$

$$\mathbf{f} = (f_{11}, \dots, f_{N1}, f_{12}, \dots, f_{N2}, \dots, f_{1C}, \dots, f_{NC})^T$$


- \mathbf{y} : a dummy encoding of y_i 's with the same layout as \mathbf{f}
- \mathbf{K} : a block diagonal matrix containing \mathbf{K}_c

$$\mathbf{K}_c = [\kappa_c(\mathbf{x}_i, \mathbf{x}_j)]$$

Gaussian Process Classification: Multi-class classification

$$\nabla \ell = -\mathbf{K}^{-1} \mathbf{f} + \mathbf{y} - \boldsymbol{\pi}$$

$$\nabla \nabla \ell = -\mathbf{K}^{-1} - \mathbf{W}$$

$$\mathbf{W} \triangleq \text{diag}(\boldsymbol{\pi}) - \boldsymbol{\Pi} \boldsymbol{\Pi}^T$$


– Use IRLS to compute the mode

$$\mathbf{f}^{new} = (\mathbf{K}^{-1} + \mathbf{W})^{-1} (\mathbf{W} \mathbf{f} + \mathbf{y} - \boldsymbol{\pi})$$

Gaussian Process Classification:

Multi-class classification

- The posterior predictive:

$$\mathbb{E} [f_{*c}] = \mathbf{k}_c(\mathbf{x}_*)^T \mathbf{K}_c^{-1} \hat{\mathbf{f}}_c = \mathbf{k}_c(\mathbf{x}_*)^T (\mathbf{y}_c - \hat{\boldsymbol{\pi}}_c)$$

$$\mathbb{E} [\mathbf{f}_*] = \mathbf{Q}_*^T (\mathbf{y} - \hat{\boldsymbol{\pi}})$$

$$\mathbf{Q}_* = \begin{pmatrix} \mathbf{k}_1(\mathbf{x}_*) & \dots & \mathbf{0} \\ & \ddots & \\ \mathbf{0} & \dots & \mathbf{k}_C(\mathbf{x}_*) \end{pmatrix}$$

Gaussian Process Classification:

Multi-class classification

- The covariance of the latent response

$$\begin{aligned}\text{cov} [\mathbf{f}_*] &= \mathbf{\Sigma} + \mathbf{Q}_*^T \mathbf{K}^{-1} (\mathbf{K}^{-1} + \mathbf{W})^{-1} \mathbf{K}^{-1} \mathbf{Q}_* \\ &= \text{diag}(\mathbf{k}(\mathbf{x}_*, \mathbf{x}_*)) - \mathbf{Q}_*^T (\mathbf{K} + \mathbf{W}^{-1})^{-1} \mathbf{Q}_*\end{aligned}$$

$$\Sigma_{cc} = \kappa_c(\mathbf{x}_*, \mathbf{x}_*) - \mathbf{k}_c^T(\mathbf{x}_*) \mathbf{K}_c^{-1} \mathbf{k}_c(\mathbf{x}_*)$$

$$\mathbf{k}(\mathbf{x}_*, \mathbf{x}_*) = [\kappa_c(\mathbf{x}_*, \mathbf{x}_*)]$$

- Computer the posterior predictive for the visible response:

$$p(y|\mathbf{x}_*, \mathbf{X}, \mathbf{y}) \approx \int \text{Cat}(y|\mathcal{S}(\mathbf{f}_*)) \mathcal{N}(\mathbf{f}_*|\mathbb{E}[\mathbf{f}_*], \text{cov}[\mathbf{f}_*]) d\mathbf{f}_*$$

Gaussian Process Classification: Multi-class classification

- **Computing the marginal likelihood**
 - similar to the binary case

$$\log p(\mathbf{y}|\mathbf{X}) \approx -\frac{1}{2}\hat{\mathbf{f}}^T \mathbf{K}^{-1} \hat{\mathbf{f}} + \mathbf{y}^T \hat{\mathbf{f}} - \sum_{i=1}^N \log \left(\sum_{c=1}^C \exp \hat{f}_{ic} \right) \\ - \frac{1}{2} \log |\mathbf{I}_{C_N} + \mathbf{W}^{\frac{1}{2}} \mathbf{K} \mathbf{W}^{\frac{1}{2}}|$$